



Schedule of Scope to Certificate of Approval
Independent Testing Laboratory
IECQ Certificate No.: IECQ-L DEKRA 17.0001
CB Certificate No.: DEKRA-C10A

Schedule Number: IECQ-L DEKRA 17.0001-S Rev No.: 2 Revision Date: 2017/11/27 Page 1 of 1

1. Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard	Remarks
Failure and material analysis of semiconductor IC, electronic components and PCB/PCBA, including FIB (Focused Ion Beam), SEM (Scanning electron microscope)	MIL-STD-883 Method 2018.4 JESD22A121 JESD201	Or customer specified test
Failure and material analysis of semiconductor IC, electronic components and PCB/PCBA, includes Electrical Analysis and Physical Analysis with Sample Preparation (Decap, X-section, etc)	MIL-STD-883 Method 2009.9 IPC-A-610 IPC-A-600 MIL-STD-883 Method 2008.4 JESD22A121 JESD201 IPC-TM-650 2.1.1 IPC-6012	Or customer specified test
Failure and material analysis of semiconductor IC, electronic components and PCB/PCBA, includes NDE (Non-destructive Testing)	MIL-STD-883 Method 2012.7 J-STD-035 J-STD-020	Or customer specified test
Electrostatic discharge test. (Including: HBM / MM / CDM / Latch Up / ESD Gun)	JESD 47 JEDEC22-A114/A115/C101 EIA/JESD78 ANSI JEDEC ESDA JS001/JS002 AEC-Q100-002/003/004/011 AEC-Q101-001/002/005 AEC-Q200-002 JEITA ED4701 IEC61000-4-2 MIL-STD-883	Or customer specified test

This schedule is only valid in conjunction with the referenced Certificate of Approval
This approval and any schedule(s) may only be reproduced in full.
This approval is not transferable and remains the property of the issuing body.
The Status and authenticity of this approval and any schedule(s) may be verified by visiting the
Official IECQ Website: www.iecq.org

DEKRA Certification B.V. Meander 1051, Arnhem. Netherlands

